ON Semiconductor®

Final Product/Process Change Notification

Document # : FPCN16790XM
Issue Date: 6 February 2018

Title of Change:	Final PCN for wafer fabrication site transfer to ON Semiconductor Niigata Co., Ltd. in Niigata, Japan (Group M)
Proposed first ship date:	13 May 2018
Contact information:	Contact your local ON Semiconductor Sales Office or <Osamu.Akaki@onsemi.com>.
Samples:	Contact your local ON Semiconductor Sales Office
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Yasuhiro.Igarashi@onsemi.com>.
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.
Change Part Identification:	Date code
Change category:	☒ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other _____

Change Sub-Category(s):

☒ Manufacturing Site Change/Addition
☐ Manufacturing Process Change
☐ Material Change
☐ Product specific change
☐ Datasheet/Product Doc change
☐ Shipping/Packaging/Marking
☐ Other: _____

Sites Affected:	ON Semiconductor Sites: ON Niigata, Japan	External Foundry/Subcon Sites: None

Description and Purpose:

This is a Final Process Change Notification to announce the addition of a new wafer fabrication site for the device covered in this notice.

Device is formerly manufactured at the Manufacturers AMPI and will be manufactured at ON Semiconductor Co., Ltd, Niigata, Japan (OSNC) following the expiration of this notice.

ON Semiconductor Niigata Co., Ltd, Niigata, Japan (OSNC) has obtained ISO9001 certification.

The product design and electrical specifications will remain identical. A full electrical characterization over the temperature range will be performed to check the device functionality and electrical specifications.

Reliability Data Summary:

QV DEVICE NAME: 1HP04CH-TL-W
RMS: 41658
PACKAGE: CPH3

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1,008 hrs	0/231
HTGB	JESD22-A108	Ta=150°C, 100% max rated Vgss	1,008 hrs	0/231
HTSL	JESD22-A103	Ta=150°C	1,008 hrs	0/231
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15,000 cyc	0/231
TC	JESD22-A104	Ta= -55°C to +150°C	1,000 cyc	0/231
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/231
Autoclave	JESD22-A102	121°C, 100% RH, 15psig, unbiased	96 hrs	0/231
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C		
RSH	JESD22- B106	Ta = 265C, 10 sec		0/90

Electrical Characteristic Summary:

There is no change in the electrical performance. Datasheet specifications remain unchanged.

List of Affected Standard Parts:

Part Number	Qualification Vehicle
1HP04CH-TL-W	1HP04CH-TL-W